## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE §

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In re Application of: Mak, et al.

Serial No.: 10/754.321

Examiner: Deo, Duy Vu Nguyen

Confirmation No.: 7484

INTEGRATED PHASE Title: ANGLE AND OPTICAL CRITICAL MEASUREMENT DIMENSION METROLOGY FOR **FFFD** FORWARD AND FEEDBACK

PROCESS CONTROL

MAIL STOP AMENDMENT Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Dear Sir:

Case: AMAT/8428/MASK/MASK-ETCH

Filed: January 9, 2004

Group Art Unit: 1765

## RESPONSE TO OFFICE ACTION DATED NOVEMBER 21, 2006

In response to the Office Action dated November 21, 2006 having a shortened statutory period for response set to expire on February 21, 2007, please enter this response and reconsider the claims pending in the application for the reasons discussed below. Although the Applicants believe there is no fee due in connection with the present matter, the Commissioner is hereby authorized to charge counsel's Deposit Account No. 20-0782 for any other fees, including additional extension of time fees or excess claim fees, required to make this response timely and acceptable to the Office.